

DUT vs DIA

Device Under Test

Device In Action

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IBIS is a Behavioral Model of a Device Under Test

IBIS is a specification of a data format that contains the following behavior of I/O buffer models:

- IV and VT curves, and measurement/threshold values are of a Device Under Test (DUT)
- The conditions of a DUT are:
 - Rail voltages are kept constant relative to a test fixture reference “Node”
 - These Rail voltages are specified by the IBIS Parameters
 - [Voltage Range]
 - [Pullup Reference]
 - [Power Clamp Reference]
 - [Pulldown Reference]
 - [GND Clamp Reference]
 - IV and VT tables are measures at the I/O buffer, and exclude all package and other parasitics that may be required to perform the test.

How Are IBIS Models Used?

- IBIS models are used in simulators to determine the time domain waveforms at various locations of a channel.
 - These models are Devices In Action (DIA).
- What rail voltages can be supplied to a DIA?
 - The same DC rail voltages that were used to generate the models data (DUT conditions)
 - Other DC rail voltages that different than the DUT rail voltages.
 - Time varying rail voltages due to
 - External voltage supply variations
 - Composite current demands from the buffer on non-ideal package models and power distributions systems

Does the IBIS Specification Tell the EDA Tool How To Use IBIS Models When Simulating in Non-DUT Conditions?

- No (Almost always – ISSO is one exception)!
- Should It?
 - How should C_comp be split between the various rails
 - Does IBIS need to spell out the current drawn from an IV table when the voltage supplied to the IV table is not the DUT value?

Positions Expressed by IBIS Members Involved in These Discussions

- No.
 - The IBIS model describes the behavior of the model under certain test conditions.
 - It is only valid at those test conditions.
 - An EDA tool is free to extrapolate that model to other operating conditions.
- Yes
 - The IBIS specification should document exactly what an EDA tool should do when the device is operating in other operating conditions
 - This way one can compare the results from different EDA tools.
- What is your opinion?